

# **CERTIFICATION TEST REPORT**

**Report Number.**: 4789754174-E10V2

**Applicant:** SAMSUNG ELECTRONICS CO., LTD.

129 SAMSUNG-RO, YEONGTONG-GU, SUWON-SI,

GYEONGGI-DO, 16677, KOREA

Model: SCG09, SC-51B

FCC ID : A3LSMG991JPN

**EUT Description**: GSM/WCDMA/LTE Phone + BT/BLE, DTS/UNII a/b/g/n/ac/ax, WPT and

**NFC** 

Test Standard(s): FCC 47 CFR PART 1 SUBPART I

FCC 47 CFR PART 2 SUBPART J

#### Date Of Issue:

February 17, 2021

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# REPORT REVISION HISTORY

Rev.	Issue Date	Revisions	Revised By
V1	02/09/21	Initial issue	Sungeun Lee
	02/17/21	Updated to address TCB's question	Sungeun Lee

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# 1. ATTESTATION OF TEST RESULTS

**COMPANY NAME:** SAMSUNG ELECTRONICS CO., LTD.

**EUT DESCRIPTION:** GSM/WCDMA/LTE Phone + BT/BLE, DTS/UNII a/b/g/n/ac/ax,

WPT and NFC

MODEL: SCG09, SC-51B

**SERIAL NUMBER:** R3CNC0392GN (RADIATED);

**DATE TESTED:** FEB 09, 2021;

#### APPLICABLE STANDARDS

**TEST RESULTS STANDARD** 

FCC PART 1 SUBPART I FCC PART 2 SUBPART J Complies

DATE: FEB 17, 2021

UL Korea, Ltd. tested the above equipment in accordance with the requirements set forth in the above standards. All indications of Pass/Fail in this report are opinions expressed by UL Korea, Ltd. based on interpretations and/or observations of test results. Measurement Uncertainties were not taken into account and are published for informational purposes only. The test results show that the equipment tested is capable of demonstrating compliance with the requirements as documented in this report.

Note: The results documented in this report apply only to the tested sample, under the conditions and modes of operation as described herein. This document may not be altered or revised in any way unless done so by UL Korea, Ltd. and all revisions are duly noted in the revisions section. Any alteration of this document not carried out by UL Korea, Ltd. will constitute fraud and shall nullify the document. This report must not be used by the client to claim product certification, approval, or endorsement by IAS, any agency of the Federal Government, or any agency of any government.

Approved & Released For

UL Korea, Ltd. By:

Tested By:

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# 2. TEST METHODOLOGY

All calculations were made in accordance with FCC OET Bulletin 65 Edition 97-01.

### 3. FACILITIES AND ACCREDITATION

The test sites and measurement facilities used to collect data are located at 218 Maeyeong-ro, Yeongtong-gu, Suwon-si, Gyeonggi-do, 16675, Korea. Line conducted emissions are measured only at the 218 address. The following table identifies which facilities were utilized for radiated emission measurements documented in this report. Specific facilities are also identified in the test results sections.

218 Maeyeong-ro
Shield Room 1

UL Korea, Ltd. is accredited by IAS, Laboratory Code TL-637. The full scope of accreditation can be viewed at <a href="https://www.iasonline.org/wp-content/uploads/2017/05/TL-637-cert-New.pdf">https://www.iasonline.org/wp-content/uploads/2017/05/TL-637-cert-New.pdf</a>.

# 4. EQUIPMENT UNDER TEST

#### 4.1. DESCRIPTION OF EUT

The EUT has WPT (Wireless Power Transfer) feature which has inductive charging coil to charge phone or watch. The charging frequency is between 110 kHz to 148 kHz, and the maximum power consumption is 9.0 W in charging status.

# 4.2. WORST-CASE CONFIGURATION

Test configuration	Description
DUT to Phone test configuration 1	Charging from Phone to DUT
DUT to Phone test configuration 2	Charging from Phone to DUT (TA Charging from DUT)
DUT to Phone test configuration 3 (cross position)	Charging from Phone to DUT
DUT to Phone test configuration 4 (cross position)	Charging from Phone to DUT (TA Charging from DUT)
DUT to Watch test configuration 5	Charging from Watch to DUT
DUT to Watch test configuration 6	Charging from Watch to DUT (TA Charging from DUT)

#### Note:

Configuration 2, 4 and 6 were tested with the worst case of configuration 1, 3 and 5.

# 4.3. KDB 680106 D01 v03 SECTION 5.b) EQUIPMENT APPROVAL CONSIDERATIONS

Requirement	Device
(1) Power transfer frequency is less than 1 MHz.	Yes. Operating Frequency is between 110kHz to 148 kHz.
(2) Output power from each primary coil is less than or equal to 15 watts.	Yes. Maximum power is 9.0 Watts.
(3) The transfer system includes only single primary and secondary coils. This includes charging systems that may have multiple primary coils and clients that are able to detect and allow coupling only between individual pairs of coils.	Yes.
(4) Client device is placed directly in contact with the transmitter.	Yes.
(5) Mobile exposure conditions only (portable exposure conditions are not covered by this exclusion).	Yes.
(6) The aggregate H-field strengths at 15 cm surrounding the device and 20 cm above the top surface from all simultaneous transmitting coils are demonstrated to be less than 50% of the MPE limit.	Yes. The aggregate field at 15 cm from the device are 7.61 % of the FCC H field limit.

#### 4.4. DESCRIPTION OF TEST SETUP

#### **SUPPORT EQUIPMENT & PERIPHERALS**

SUPPROT EQUIPMENT & PERIPHERALS LIST							
Description	Manufacturer	Model	Serial Numver	FCC ID			
Phone	Samsung Electronics Co., Ltd.	SM-G986B/DS	R3CMB0C70XN	A3LSMG986B			
Watch	Samsung Electronics Co., Ltd.	SM-R835F	RFAM90ZXFTF	A3LSMR835			
Traver Adapter	Samsung Electronics Co., Ltd.	EP-TA800	-	-			
USB Data Cable	Samsung Electronics Co., Ltd.	EP-DN980BBE	-	-			

#### **TEST SETUP**

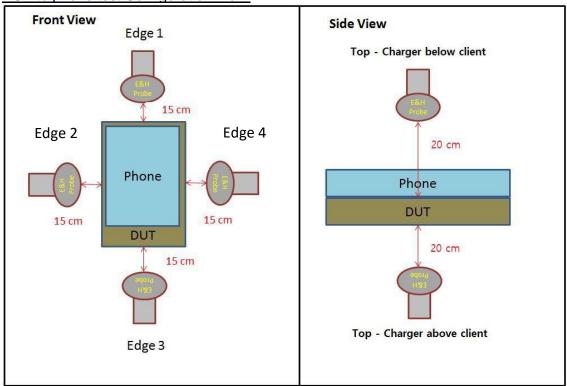
The following three modes are tested in test configurations;

Mode
Operating (SUPPORT Equipment, <10% Power Charging)
Operating (SUPPORT Equipment, 50~55% Power Charging)
Operating (SUPPORT Equipment, 90~95% Power Charging)

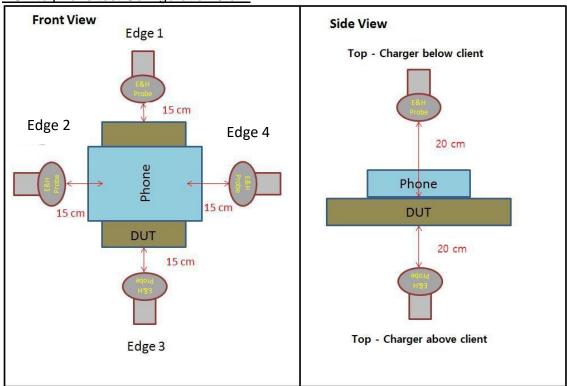
#### **MEASUREMENT TEST SETUP**

The measurement was taken using a probe placed 15 cm surrounding the device and 20 cm above the top surface of the EUT. Measurements were taken the top (charger below/above client) and all sides of the EUT per KDB680106 D01 v03 and RF Exposure Procedures (Wireless Power Transfer) in TCB Workshop October, 2018.

#### DUT to phone test Configuration 1 & 2



# DUT to phone test Configuration 3 & 4



DUT to Watch test Configuration 5 & 6 **Front View** Side View Edge 1 Top - Charger below client 15 cm Edge 4 Edge 2 Watch 20 cm 15 cm 15 cm Watch DUT DUT 15 cm Edge 3

# 5. TEST AND MEASUREMENT EQUIPMENT

The following test and measurement equipment was used for the tests documented in this report;

Test Equipment List							
Description	Manufacturer	Model	Serial Numver	Cal Date	Cal Due		
Electric and Magnetic Field Probe	Narda	EHP-200AC	170WX91008	8-12-2020	8-12-2021		

# 6. Maximum PERMISSIBLE RF EXPOSURE

#### FCC LIMITS AND SUMMARY

#### 6.1.1. FCC LIMITS

§ 1.1310 The criteria listed in Table 1 shall be used to evaluate the environmental impact of human exposure to radio-frequency (RF) radiation as specified in § 1.1307(b), except in the case of portable devices which shall be evaluated according to the provisions of § 2.1093 of this chapter.

TABLE 1—LIMITS FOR MAXIMUM PERMISSIBLE EXPOSURE (MPE)

Frequency range (MHz)	Electric field strength (V/m)	Magnetic field strength (A/m)	Power density (mW/cm²)	Averaging time (minutes)				
(A) Lim	(A) Limits for Occupational/Controlled Exposures							
0.3–3.0	614	1.63	*(100)	6				
3.0-30	1842/f	4.89/f	*(900/f <sup>2</sup> )	6				
30–300	61.4	0.163	1.0	6				
300–1500			f/300	6				
1500–100,000			5	6				
(B) Limits	for General Populati	on/Uncontrolled Exp	oosure					
0.3–1.34	614	1.63	*(100)	30				
1.34–30	824/f	2.19/f	*(180/f <sup>2</sup> )	30				

TABLE 1—LIMITS FOR MAXIMUM PERMISSIBLE EXPOSURE (MPE)—Continued

Frequency range (MHz)	Electric field strength (V/m)	Magnetic field strength (A/m)	Power density (mW/cm <sup>2</sup> )	Averaging time (minutes)
30–300	27.5	0.073	0.2 f/1500	30 30 30

f = frequency in MHz

\* = Plane-wave equivalent power density

Note 1 to Table 1: Occupational/controlled limits apply in situations in which persons are exposed as a consequence of their employment provided those persons are fully aware of the potential for exposure and can exercise control over their exposure. Limits for occupational/controlled exposure also apply in situations when an individual is transient through a location where occupational/controlled limits apply provided he or she is made aware of the potential for exposure.

Note 2 to Table 1: General population/uncontrolled exposures apply in situations in which the general public may be exposed, or in which persons that are exposed as a consequence of their employment may not be fully aware of the potential for exposure or can not exercise control over their exposure.

# 6.2. TEST RESULTS

#### 6.2.1. FCC RF EXPOSURE

#### **H-FIELD MEASUREMENTS**

Note: Peak measurement were performed. RMS values were calculated from the peak measurement.

Please refer to the formula for calculating the RMS values: [Field Strength x  $\sqrt{\text{Duty Cycle}}$ ]. Additional test was performed in each Test mode by moving the probe surrounding the device to find the maximum exposure.

#### TEST results of DUT to phone test Configuration 1 & 2

Test Configuration	Test mode	Test distance	Test Position	H-Field Limit (A/m)	H-Field meas data (A/m)
			Top - charger above client		0.017
			Top - charger below client		0.018
			Edge 1		0.022
	Operating Real Product (Power <10% charging)		Edge 2		0.020
	(1 0 1 0 1 1 0 7 0 0 1 1 a 1 g 1 1 g )		Edge 3		0.019
			Edge 4		0.019
	(Power 50~55% charging)	15 cm probe to edges of EUT and 20 cm probe to top surface of the EUT	max	1.63	0.022
			Top - charger above client		0.018
			Top - charger below client		0.018
			Edge 1		0.022
Configuration 1			Edge 2		0.020
			Edge 3		0.019
			Edge 4		0.018
			max		0.022
			Top - charger above client		0.019
			Top - charger below client		0.017
			Edge 1		0.023
	Operating Real Product (Power 90~95% charging)		Edge 2		0.023
	(Powel 30~33 // Charging)		Edge 3		0.018
			Edge 4		0.018
		]	max		0.023
Configuration 2	Operating Real Product		Edge 1		0.023
Corniguration 2	(Power 90~95% charging)		max		0.026

TEST results of DUT to phone test Configuration 3 & 4

Test Configuration	Test mode	Test distance	Test Position	H-Field Limit (A/m)	H-Field meas data (A/m)
			Top - charger above client		0.056
			Top - charger below client		0.120
			Edge 1		0.049
	Operating Real Product (Power <10% charging)		Edge 2		0.093
	(i one: 110/0 onaiging)		Edge 3		0.091
			Edge 4		0.120
			max		0.120
	Operating Real Product (Power 50~55% charging)	15 cm probe to edges of EUT and 20 cm probe to top surface of the EUT	Top - charger above client	1.63	0.057
			Top - charger below client		0.120
			Edge 1		0.049
Configuration 3			Edge 2		0.090
			Edge 3		0.090
			Edge 4		0.121
			max		0.121
			Top - charger above client		0.059
	Operating Real Product (Power 90~95% charging)		Top - charger below client		0.118
			Edge 1		0.044
			Edge 2		0.091
	(. 1 55 55/5 5gillg)		Edge 3		0.090
			Edge 4		0.122
			max		0.122
Configuration 4	Operating Real Product		Edge 4		0.122
Corniguration 4	(Power 90~95% charging)		max		0.124

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TEST results of DUT to phone test Configuration 5 & 6

FCC RF Exposure Result						
Test Configuration	Test mode	Test distance	Test Position	H-Field Limit (A/m)	H-Field meas data (A/m)	
Configuration 5	Operating Real Product (Power <10% charging)	15 cm probe to edges of EUT and 20 cm probe to top surface of the EUT	Top - charger below client	1.63	0.077	
			Edge 1		0.018	
			Edge 2		0.027	
			Edge 3		0.020	
			Edge 4		0.053	
			max		0.077	
	Operating Real Product (Power 50~55% charging)		Top - charger below client		0.075	
			Edge 1		0.017	
			Edge 2		0.027	
			Edge 3		0.020	
			Edge 4		0.054	
			max		0.075	
	Operating Real Product (Power 90~95% charging)		Top - charger below client		0.079	
			Edge 1		0.019	
			Edge 2		0.028	
			Edge 3		0.021	
			Edge 4		0.055	
			max		0.079	
Configuration 6	Operating Real Product (Power <10% charging)		Top - charger below client		0.079	
			max		0.080	

# 6.2.2. FCC SUMMARY OF RESULTS

H-Field Limit					
FCC RF Exposure	Maximum meas data (A/m)	Percentage (%)			
1.63	0.124	7.61			
Conclusion:					

H-Field result is less than 50% of the MPE limit.

# **END OF TEST REPORT**